		Application/Control No.		Applicant(s)/Pat	Applicant(s)/Patent under Reexamination	tion
Issue Classification	ation	10822167		CHAE ET AL.		
	=	Examiner Wendler, Eric		Art Unit 2824		
	ORIGINAL		INTE	RNATIONAL	INTERNATIONAL CLASSIFICATION	Z
CLASS		SUBCLASS	CLAIMED	ED	NON-CLAIMED	AIMED
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CROS	CROSS REFERENCE(S))E(S)				
CLASS SUBCL	SUBCLASS (ONE SUBCLASS P	CLASS PER BLOCK)				
365 230.06	230.08	185.29 218	T			
Eric J. Wendler	7/20/06	MA	01111010		Total Claims Allowed:	Allowed:
(Assistant Examiner)	(Date)	/ W/ masts superv	MICHARU ELMIS MASICO SUPERVISORY PATENT EXAMINER	R	21	
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(Legal Instruments Examiner)	(Date)	(Primary Examiner)	(Date)		-	5

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